Application/Control No.	Applicant(s)/Patent under Reexamination
10/080,145	BAEG ET AL.
Examiner	Art Unit
John P. Trimmings	2138

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
714	712	2/27/2006	JPT
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
NPL Search: Author, testing scan cell differential null detect.	2/27/2006	JPT
Dble Patent Search: Negative.	2/27/2006	JPT
Class Search: 714/712,709,727,821, 702/117, 714/48.	2/27/2006	JPT
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